



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of : **Confirmation No. 2264**
Yoshiki SUGETA et al. : Attorney Docket No. 2003_0880A
Serial No. 10/602,883 : Group Art Unit 1756
Filed June 25, 2003 : Examiner C. G. Young
METHOD OF FORMING FINE PATTERNS **Mail Stop: RCE**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to the provisions of 37 CFR 1.56, 1.97 and 1.98, Applicants request consideration of the references listed on attached form PTO-1449 and any additional information identified below in paragraph 3. A legible copy of each reference listed on the Form PTO-1449 is enclosed, except a copy is not provided for:

- ☒ each U.S. Patent and U.S. Patent application publication;
- ☐ each reference previously cited in the international application PCT/_____; and/or
- ☐ each reference previously cited in prior parent application Serial No. _____.

1a. ☒ This Information Disclosure Statement is submitted:

within three months of the filing date (or of entry into the National Stage) of the above-entitled application, **or**

before the mailing of a first Office Action on the merits or the mailing of a first Office Action after the filing of an RCE,

and thus no certification and/or fee is required.

1b. ☐ This Information Disclosure Statement is submitted

after the events of above paragraph 1a and prior to the mailing date of a final Office Action or a Notice of Allowance or an action which otherwise closes prosecution in the application, and thus:

(1) ☐ the certification of paragraph 2 below is provided, **or**

(2) ☐ the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.

1c. ☐ This Information Disclosure Statement is submitted:

after the mailing date of a final Office Action or Notice of Allowance or action which otherwise closes prosecution in the application, and prior to payment of the issue fee, and thus:

the certification of paragraph 2 below is provided, and

the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.

2. It is hereby certified

a. ☐ that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or

b. ☐ that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in §1.56(c) more than three months prior to the filing of the Statement.

3. ☐ Consideration of the following list of additional information (including any copending or abandoned U.S. application, prior uses and/or sales, etc.) is requested.

4. For each non-English language reference listed on the attached form PTO-1449, reference is made to:

a. ☐ a full or partial English language translation submitted herewith,

- b. ☐ a foreign patent office search report (in the English language) submitted herewith,
- c. ☐ the concise explanation contained in the specification of the present application at page,
- d. ☐ the concise explanation set forth in the attached English language abstract,
- e. ☒ the concise explanation set forth below or on a separate sheet attached to the reference:

1. References AJ, AK, AL, AM, AN, AO, and AP are listed in the column entitled Record of the result of prior art search in the JPO Office Action (November 9, 2004). However, the Office Action states that such Record is not a component of the reasons for refusal.

2. References AC, AD, AQ, AR and AS are not enclosed herewith, but will follow shortly along with a copy of the JPO Office Action dated November 9, 2004.

3. Reference AC corresponds to U.S. 6,555,607


4. References AB and AC were cited by the Chinese Patent Office in an Official Action dated October 15, 2004.

- 5. ☐ A foreign patent office search report citing one or more of the references is enclosed.
- 6. ☐ Statement Under 37 CFR 1.704(d)

Each item of information contained in the Information Disclosure Statement was first cited in any communication from a foreign Patent Office in a counterpart application, and this communication was not received by any individual designated in §1.56(c) more than thirty days prior to the filing of the Information Disclosure Statement.

Respectfully submitted,

Yoshiki SUGETA et al.

By 
Matthew M. Jacob
Registration No. 25,154
Attorney for Applicants

MJ/kjf
Washington, D.C. 20006-1021
Telephone (202) 721-8200
Facsimile (202) 721-8250
August 21, 2006

**THE COMMISSIONER IS AUTHORIZED
TO CHARGE ANY DEFICIENCY IN THE
FEES FOR THIS PAPER TO DEPOSIT
ACCOUNT NO. 23-0975**

INFORMATION DISCLOSURE STATEMENT

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
2003_0880ASERIAL NO.
10/602,883LIST OF REFERENCES CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Yoshiki SUGETA et al.

Date Submitted to PTO: August 21, 2003

FILING DATE
June 25, 2003GROUP
1756

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AB	7-45510	02/1995	JP			Abstract
	AC	1314931 A	09/2001	CN			
	AD	64-023535	01/1989	JP			Abstract
	AE	1-307228	12/1989	JP			Abstract
	AF	4-364021	12/1992	JP			Abstract
	AH	5-166717	07/1993	JP			Abstract
	AI	5-241348	09/1993	JP			Abstract
	AJ	10-73927	03/1998	JP			Abstract
	AK	2000-347414	12/2000	JP			Abstract
	AL	2001-19860	01/2001	JP			Abstract
	AM	2001-109165	04/2001	JP			Abstract
	AN	2001-281886	10/2001	JP			Abstract
	AO	11-283910	10/1999	JP			Abstract
	AP	11-204399	07/1999	JP			Abstract

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	"Extended Abstracts", (The 42 nd Spring Meeting, 1995); <i>The Japan Society of Applied Physics and Related Societies</i> , No. 2.
	AR	"Extended Abstracts", (The 55 th Autumn Meeting, 1994); <i>The Japan Society of Applied Physics</i> , No. 2
	AS	<i>Proceedings SPIE</i> , Vol. 4345, pp. 647 to 654.

EXAMINER

DATE CONSIDERED